

74ACT843 9-Bit Transparent Latch

General Description

The ACT843 bus interface latch is designed to eliminate the extra packages required to buffer existing latches and provide extra data width for wider address/data paths.

The ACT843 is functionally and pin compatible with AMD's Am29843.

Features

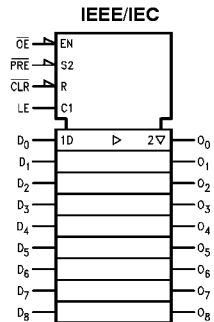
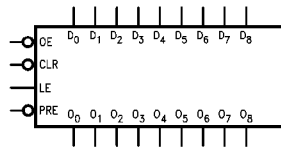
- Has TTL-compatible inputs
- 3-STATE outputs for bus interfacing

Ordering Code:

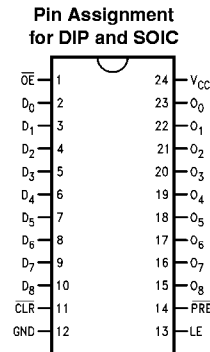
Order Number	Package Number	Package Description
74ACT843SC	M24B	24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
74ACT843SPC	N24C	24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-010, 0.600" Wide

Device also available in Tape and Reel. Specify by appending suffix letter "X" to the ordering code. (SPC not available in Tape and Reel.)

Logic Symbols



Connection Diagram



Pin Descriptions

Pin Names	Description
D ₀ -D ₈	Data Inputs
O ₀ -O ₈	Data Outputs
\overline{OE}	Output Enable
LE	Latch Enable
\overline{CLR}	Clear
\overline{PRE}	Preset

Functional Description

The ACT843 consists of nine D-type latches with 3-STATE outputs. The flip-flops appear transparent to the data when Latch Enable (LE) is HIGH. This allows asynchronous operation, as the output transition follows the data in transition. On the LE HIGH-to-LOW transition, the data that meets the setup times is latched. Data appears on the bus when the Output Enable (\overline{OE}) is LOW. When \overline{OE} is HIGH, the bus output is in the high impedance state. In addition to

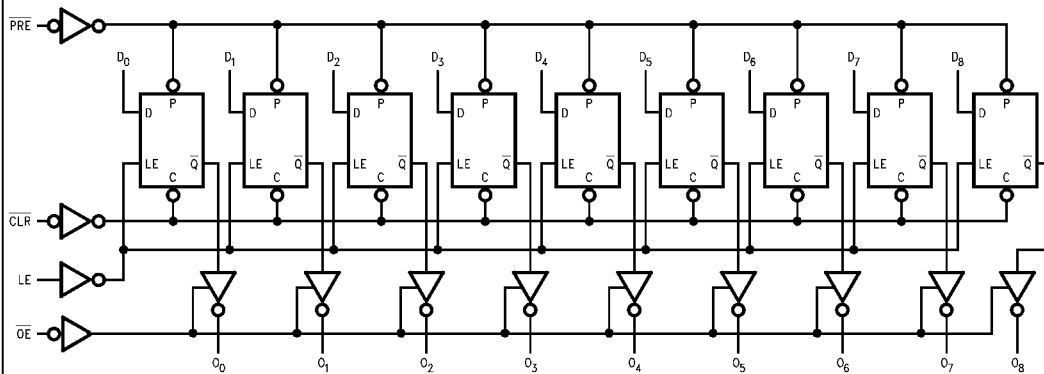
the LE and \overline{OE} pins, the ACT843 has a Clear (\overline{CLR}) pin and a Preset (\overline{PRE}) pin. These pins are ideal for parity bus interfacing in high performance systems. When \overline{CLR} is LOW, the outputs are LOW if \overline{OE} is LOW. When \overline{CLR} is HIGH, data can be entered into the latch. When \overline{PRE} is LOW, the outputs are HIGH if \overline{OE} is LOW. Preset overrides \overline{CLR} .

Function Tables

Inputs					Internal	Outputs	Function
\overline{CLR}	\overline{PRE}	\overline{OE}	LE	D	Q	O	
H	H	H	H	L	L	Z	High Z
H	H	H	H	H	H	Z	High Z
H	H	H	L	X	NC	Z	Latched
H	H	L	H	L	L	L	Transparent
H	H	L	H	H	H	H	Transparent
H	H	L	L	X	NC	NC	Latched
H	L	L	X	X	H	H	Preset
L	H	L	X	X	L	L	Clear
L	L	L	X	X	H	H	Preset
L	H	H	L	X	L	Z	Clear/High Z
H	L	H	L	X	H	Z	Preset/High Z

H = HIGH Voltage Level
 L = LOW Voltage Level
 X = Immaterial
 Z = High Impedance
 NC = No Change

Logic Diagram



Absolute Maximum Ratings ^(Note 1)		Junction Temperature (T_J)
Supply Voltage (V_{CC})	-0.5V to +7.0V	PDIP 140°C
DC Input Diode Current (I_{IK})		
$V_I = -0.5V$	-20 mA	
$V_I = V_{CC} + 0.5V$	+20 mA	
DC Input Voltage (V_I)	-0.5V to $V_{CC} + 0.5V$	
DC Output Diode Current (I_{OK})		
$V_O = -0.5V$	-20 mA	
$V_O = V_{CC} + 0.5V$	+20 mA	
DC Output Voltage (V_O)	-0.5V to $V_{CC} + 0.5V$	
DC Output Source		
or Sink Current (I_O)	± 50 mA	
DC V_{CC} or Ground Current		
per Output Pin (I_{CC} or I_{GND})	± 50 mA	
Storage Temperature (T_{STG})	-65°C to +150°C	

Recommended Operating Conditions	
Supply Voltage (V_{CC})	4.5V to 5.5V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A)	-40°C to +85°C
Minimum Input Edge Rate ($\Delta V/\Delta t$)	125 mV/ns
	V_{IN} from 0.8V to 2.0V
	V_{CC} @ 4.5V, 5.5V

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. Fairchild does not recommend operation of FACT™ circuits outside databook specifications.

DC Electrical Characteristics

Symbol	Parameter	V_{CC} (V)	$T_A = +25^\circ\text{C}$		$T_A = -40^\circ\text{C to } +85^\circ\text{C}$		Units	Conditions
			Typ	Guaranteed Limits				
V_{IH}	Minimum HIGH Level Input Voltage	4.5	1.5	2.0	2.0	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$	
		5.5	1.5	2.0	2.0			
V_{IL}	Maximum LOW Level Input Voltage	4.5	1.5	0.8	0.8	V	$V_{OUT} = 0.1V$ or $V_{CC} - 0.1V$	
		5.5	1.5	0.8	0.8			
V_{OH}	Minimum HIGH Level Output Voltage	4.5	4.49	4.4	4.4	V	$I_{OUT} = -50 \mu A$	
		5.5	5.49	5.4	5.4			
		4.5		3.86	3.76	V	$V_{IN} = V_{IL}$ or V_{IH} $I_{OH} = -24$ mA $I_{OH} = -24$ mA (Note 2)	
		5.5		4.86	4.76			
V_{OL}	Maximum LOW Level Output Voltage	4.5	0.001	0.1	0.1	V	$I_{OUT} = 50 \mu A$	
		5.5	0.001	0.1	0.1			
		4.5		0.36	0.44	V	$V_{IN} = V_{IL}$ or V_{IH} $I_O = 24$ mA $I_{OL} = 24$ mA (Note 2)	
		5.5		0.36	0.44			
I_{IN}	Maximum Input Leakage Current	5.5		± 0.1	± 1.0	μA	$V_I = V_{CC}, GND$	
I_{OZ}	Maximum 3-STATE Leakage Current	5.5		± 0.5	± 5.0	μA	$V_I = V_{IL}, V_{IH}$ $V_O = V_{CC}, GND$	
I_{CC}	Maximum $I_{CC}/Input$	5.5	0.6		1.5	mA	$V_I = V_{CC} - 2.1V$	
I_{OLD}	Minimum Dynamic	5.5			75	mA	$V_{OLD} = 1.65V$ Max	
I_{OHD}	Output Current (Note 3)	5.5			-75	mA	$V_{OHD} = 3.85V$ Min	
I_{CC}	Maximum Quiescent Supply Current	5.5		8.0	80.0	μA	$V_{IN} = V_{CC}$ or GND	

Note 2: All outputs loaded; thresholds on input associated with output under test.

Note 3: Maximum test duration 2.0 ms, one output loaded at a time.

AC Electrical Characteristics								
Symbol	Parameter	V _{CC} (V) (Note 4)	T _A = +25°C			T _A = -40°C to -85°C		Units
			C _L = 50 pF			C _L = 50 pF		
			Min	Typ	Max	Min	Max	
t _{PLH}	Propagation Delay D _n to O _n	5.0	2.5	5.5	9.5	2.0	10.0	ns
t _{PHL}	Propagation Delay D _n to O _n	5.0	2.5	5.5	9.5	2.0	10.0	ns
t _{PLH}	Propagation Delay LE to O _n	5.0	2.5	5.5	9.0	2.0	10.0	ns
t _{PHL}	Propagation Delay LE to O _n	5.0	2.5	5.5	9.0	2.0	10.0	ns
t _{PLH}	Propagation Delay $\overline{\text{PRE}}$ to O _n	5.0	2.5	6.5	14.0	2.0	16.0	ns
t _{PHL}	Propagation Delay $\overline{\text{CLR}}$ to O _n	5.0	2.5	7.5	15.5	2.0	17.5	ns
t _{PZH}	Output Enable Time $\overline{\text{OE}}$ to O _n	5.0	2.5	5.5	9.5	2.0	10.5	ns
t _{PZL}	Output Enable Time $\overline{\text{OE}}$ to O _n	5.0	2.5	5.5	9.5	2.0	10.5	ns
t _{PHZ}	Output Disable Time $\overline{\text{OE}}$ to O _n	5.0	2.5	6.0	10.5	2.0	11.0	ns
t _{PLZ}	Output Disable Time $\overline{\text{OE}}$ to O _n	5.0	2.5	6.0	10.5	2.0	11.0	ns
t _{PHL}	Propagation Delay $\overline{\text{PRE}}$ to O _n	5.0	2.5	6.0	10.5	2.0	11.0	ns
t _{PLH}	Propagation Delay $\overline{\text{CLR}}$ to O _n	5.0	2.5	5.5	9.5	2.0	10.5	ns

Note 4: Voltage Range 5.0 is 5.0V ±0.5V

AC Operating Requirements

Symbol	Parameter	V _{CC} (V) (Note 5)	T _A = +25°C		T _A = -40°C to +85°C		Units
			C _L = 50 pF		C _L = 50 pF		
			Typ	Guaranteed Minimum			
t _S	Setup Time, HIGH or LOW D _n to LE	5.0	-0.5	0.5	1.0		ns
t _H	Hold Time, HIGH or LOW D _n to LE	5.0	0.5	2.0	2.0		ns
t _W	LE Pulse Width, HIGH	5.0	2.0	3.5	3.5		ns
t _W	PRE Pulse Width, LOW	5.0	5.0	8.5	10.0		ns
t _W	CLR Pulse Width, LOW	5.0	5.5	9.5	11.0		ns
t _{rec}	PRE Recovery Time	5.0	0.5	2.0	2.0		ns
t _{rec}	CLR Recovery Time	5.0	-0.5	1.0	1.0		ns

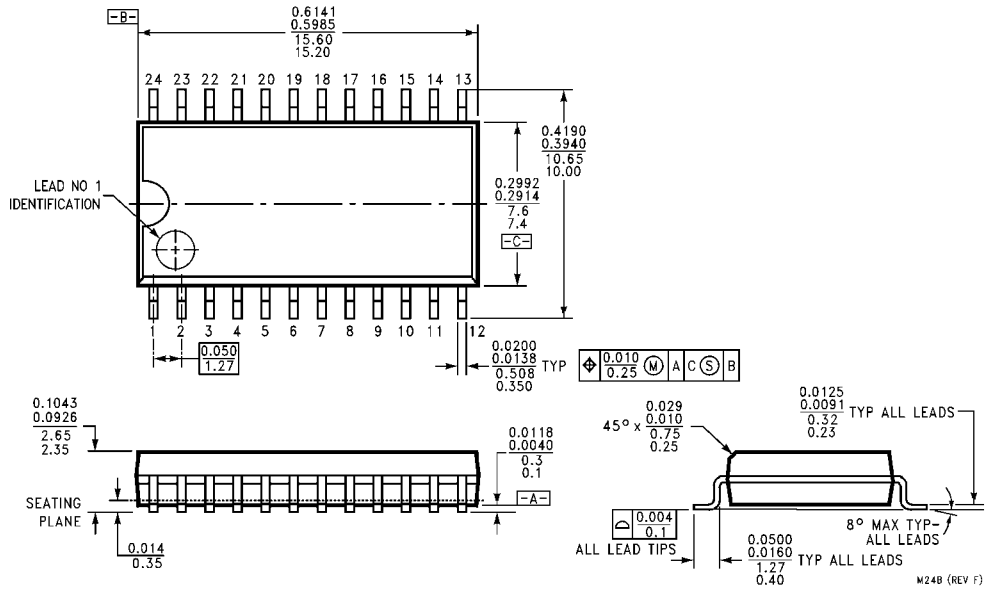
Note 5: Voltage Range 5.0 is 5.0V ±0.5V

Capacitance

Symbol	Parameter	Typ	Units	Conditions
C _{IN}	Input Capacitance	4.5	pF	V _{CC} = OPEN
C _{PD}	Power Dissipation Capacitance	44	pF	V _{CC} = 5.0V

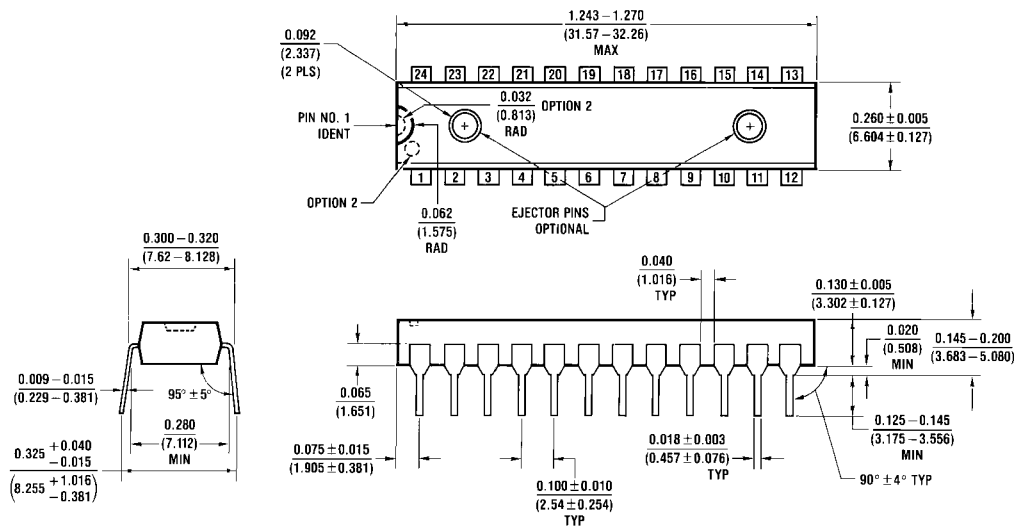
74ACT843

Physical Dimensions inches (millimeters) unless otherwise noted



**24-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300" Wide Body
Package Number M24B**

Physical Dimensions inches (millimeters) unless otherwise noted (Continued)



**24-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-100, 0.300" Wide
 Package Number N24C**

N24C (REV F)

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